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U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
H0001468

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P. 03/17

LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Honeywell International Inc.PILING DATE  
October 24, 2000GROUP  
1753

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
Gm	AA	2,949,357	08/1960	Resnick	148	421	
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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
gm	AM	JP1092338	04/1969	Japan				
	AN	GB 810533	03/1959	Great Britain				
	AO	JP57019372	02/1982	Japan				
	AP	JP200273623	10/2000	Japan				
	AQ	SUL5820R3	09/1996	SU				

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EXAMINER

*Hobayn A. Donald*

DATE CONSIDERED

*1-14-03*\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.  
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. H0001468	SERIAL NO. 09/695,814		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Honeywell International Inc.			
				FILING DATE October 24, 2000	GROUP 1753		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>mr</i>	AA	5,939,788	08/1999	McTeer	0	257	751
<i>mr</i>	AB	4,903,117	02/1990	Okamoto et al.	0	257	751
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		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
<i>mr</i>	AM	WO 00/13235	09/03/2000	PCT	0		
	AN	08120445	14/05/1996	Japan	0		
	AO	FR 2 585 730 A1	08/01/1985	France	1		
	AP	GB 2 202 237 A	21/09/1988	GB	2		
<i>mr</i>	AQ	11074348	16/03/1999	Japan	0		
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
<i>mr</i>	AS		Knotek et al., "The Structure and Composition of Ti-Zr-N, Ti-Al-Zr-N and Ti-Al-V-N Coatings" Materials Science and Engineering, A105/106, December 1988, pgs. 481-488.				
<i>mr</i>	AT		Sakamoto et al., "Preparation and Microstructure of Reactively Sputtered Ti <sub>x</sub> Zr <sub>y</sub> N Films" Thin Solid Films 228, May 1993, pgs. 169-172.				
	AU						
EXAMINER <i>Padley or Donald</i>				DATE CONSIDERED <i>1-14-03</i>			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							

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Stephen P. Turner et al.FILING DATE  
October 24, 2000GROUP  
1753

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Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>Thru</i>	AA	5,171,379	12/1992	Kumar et al.	148	472	
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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>Thru</i>	AM	252,442	09.06.1960	Australia	1			
<i>Thru</i>	AN	55-179784	12/1980	Japan	1			
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<i>Thru</i>	AR		Hughes et al., "Grain Subdivision and the Development of Local Orientations in Rolled Tantalum" Tantalum. The Minerals, Metals & Materials Society, 1996. pgs. 257-262. (Year is sufficiently early so that the month is not an issue.)	1				
	AS		Arlt, Jr., "Sulfonation and Sulfonation to Thorium and Thorium Compounds" Kirk-Othmer Encyclopedia of chemical Technology vol. 22, pp. 541-564. (1993. Year is sufficiently early so that the month is not an issue.)	1				
<i>Thru</i>	AT		Kirkbride et al., "The Effect of Yttrium on the Recrystallization and Grain Growth of Tantalum", J. Less-Common Metals. vol. 9, pp. 393-408. 1965. (Year is sufficiently early so that the month is not an issue.)	1				

EXAMINER: *Stephen P. Turner*

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1-14-03

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		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AB						No

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AC	National Research Corporation Press Release, pgs. 1-4, July 1964.	1
	AD	National Research Corporation Data Sheet "SGS Tantalum", pgs. 1-7, no date.	1
	AD	ASTM Standard Specification for Tantalum and Tantalum Alloy Plate, Sheet, and Strip, pgs. 558-561, 1992. (Year is sufficiently early so that the month is not an issue.)	1
	AE	Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Materials Research Society Symposium Proceedings, vol. 322, pgs. 413-422, 1994. (Year is sufficiently early so that the month is not an issue.)	1
	AF	Kumar, et al. "Effect of Intermetallic Compounds of the Properties of Tantalum" Refractory Metals & Hard Materials, vol. 12, pgs. 35-40, 1994. (Year is sufficiently early so that the month is not an issue.)	1
	AG	Klein et al., "Inhomogeneous Textures in Tantalum Sheets" Materials Science Forum, vol. 157-162, pgs. 1423, (1994). (Year is sufficiently early so that the month is not an issue.)	1
	AH	Clark et al., "Influence of Transverse Rolling on the Microstructural and Texture Development in Pure Tantalum", Metallurgical Transactions, vol. 23A, pgs. 2183-2191, August 1992.	1
	AI	Raabe, et al., "Texture and Microstructure of Rolled and Annealed Tantalum". Materials Science and Technology, Vol. 10, pgs. 299-305, April 1994.	1
	AJ	Wright et al., "Texture Gradient Effects in Tantalum", International Conference on Textures of Materials, 7 pgs., September 1993.	1
	AK	Wright et al., "Textural and Microstructural Gradient Effects on the Mechanical Behavior of a Tantalum Plate", Metallurgical Transactions A, 25A (1994), pgs. 1-17. (Year is sufficiently early so that the month is not an issue.)	1
	AL	Clark et al., "Effect of Processing Variables on Texture and Texture Gradients in Tantalum", Metallurgical Transactions A, Vol. 22A, September 1991, pgs. 2039-2047.	1
	AM	Kumar et al., "Corrosion Resistant Properties of Tantalum" Corrosion 95, Paper No. 253, 14 pages. (No date)	1
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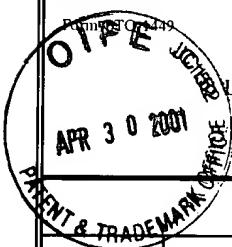
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<p style="text-align: center;">U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</p> <p style="text-align: center;">LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p> <p style="text-align: right;">APR 30 2001</p> <p style="text-align: right;">OPIPE REC'D</p>		ATTY. DOCKET NO. H0001468 (HO58-044)		SERIAL NO. 09/695,814				
		APPLICANT Honeywell International, Inc. (Pennsylvania)						
		FILING DATE October 24, 2000		GROUP Unassigned				
		U.S. PATENT DOCUMENTS						
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>Opie</i>	AA	6,024,847	02/15/00	Rosenberg et al.	304	243.1	<i>RECEIVED</i> <i>MAY 2 2001</i>	
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EXAMINER <i>Tobey M. Donald</i>				DATE CONSIDERED <i>1-14-03</i>				
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09/695,814

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APPLICANT  
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Unassigned

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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>Y</i>	AA	60/225,518 (Serial No.) As filed and amended		Jianxing Li et al.			08/15/00
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## FOREIGN PATENT DOCUMENTS

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EXAMINER:

*Kathy M. Dorrell*

DATE CONSIDERED

*1-14-03*

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